

**Amendments to the Specification:**

Please replace paragraph beginning at line 8, page 7, which starts with "Fig. 1 shows" with the following amended paragraph:

Fig. 1a shows a first embodiment according to the present invention. As an example and not limiting to the present invention it is referred to inspection of a specimen. An emitter array system 10 emits a plurality of electron beams 8, to inspect integrated circuits on a specimen 16. The specimen is located on specimen stage 18, which is capable of moving the specimen with respect to the electron beams 8. A lens ~~(not shown)~~ 13 generates a magnetic lens field 12' (B) to focus the electron beams on the specimen.